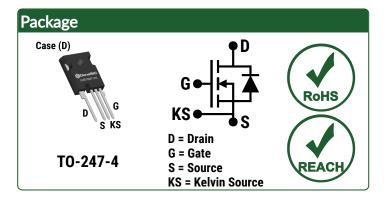
GeneSic SEMICONDUCTOR

Silicon Carbide MOSFET N-Channel Enhancement Mode

 V_{DS} = 1200 V $R_{DS(ON)(Typ.)}$ = 75 mΩ I_{D} (Tc = 100°C) = 23 A

Features

- G3R™ SiC MOSFET Technology
- Superior Q_G x R_{DS(ON)} Figure of Merit
- Low Capacitances and Low Gate Charge
- Normally-Off Stable Operation up to 175°C
- Fast and Reliable Body Diode
- High Avalanche and Short Circuit Ruggedness
- Low Conduction Losses at High Temperatures
- Optimized Package with Separate Driver Source Pin



Advantages

- Increased Power Density for Compact System
- High Frequency Switching
- Reduced Losses for Higher System Efficiency
- Minimized Gate Ringing
- Improved Thermal Capabilities
- High Cost-Performance Index
- Ease of Paralleing without Thermal Runaway
- Simple to Drive

Applications

- Solar Inverters
- EV/HEV Charging
- UPS
- High Voltage DC-DC Converters
- Switched Mode Power Supplies
- Motor Drives
- Smart Grid Transmission and Distribution
- Induction Heating and Welding

Absolute Maximum Ratings (At T_C = 25°C Unless Otherwise Stated) **Parameter Symbol Conditions Values** Unit Note **Drain-Source Voltage** $V_{GS} = 0 \text{ V, } I_D = 100 \text{ } \mu\text{s}$ 1200 ٧ $V_{DS(max)}$ Gate-Source Voltage (Dynamic) -10 / +25 ٧ $V_{GS(max)}$ Gate-Source Voltage (Static) -5/+20٧ $V_{GS(op)}$ **Recommended Operation** $T_C = 100$ °C, $V_{GS} = 20 \text{ V}$ 23 **Continuous Forward Current** I_D Α Fig. 15 $T_C = 135^{\circ}C$, $V_{GS} = 20 \text{ V}$ 17 **Pulsed Drain Current** $t_P \le 10\mu s$, $D \le 1\%$, Note 1 80 Fig. 14 I_{D(pulse)} Α $T_c = 25$ °C 123 W **Power Dissipation** P_D Fig. 16 Operating and Storage Temperature -55 to 175 °C T_j , T_{stg}

Thermal/Package Characteristics								
Parameter	Symbol	Conditions	Values			- Unit	Note	
			Min.	Тур.	Max.	UIIIL	Note	
Thermal Resistance, Junction - Case	R_{thJC}			1.22		°C/W	Fig. 13	
Weight	W _T			6.1		g		
Mounting Torque	Тм	Screws to Heatsink			1.1	Nm		

Note 1: Pulse Width t_P Limited by $T_{j(max)}$





Parameter	Symbol	Conditions	Values			Heit	Nese
			Min.	Тур.	Max.	Unit	Note
Drain-Source Breakdown Voltage	V_{DSS}	V_{GS} = 0 V, I_D = 100 μA	1200			V	
Zero Gate Voltage Drain Current	I _{DSS}	V_{DS} = 1200 V, V_{GS} = 0 V		1		μΑ	
Gate Source Leakage Current	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = 25 \text{ V}$ $V_{DS} = 0 \text{ V}, V_{GS} = -10 \text{ V}$			100 -100	nA	
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 7.5 \text{ mA}$ $V_{DS} = V_{GS}, I_D = 7.5 \text{ mA}, T_j = 175^{\circ}\text{C}$	2.3	3.0 2.1	4.0	٧	Fig. 9
Transconductance	G fs	$V_{DS} = 10 \text{ V, } I_D = 20 \text{ A}$ $V_{DS} = 10 \text{ V, } I_D = 20 \text{ A, } T_j = 175^{\circ}\text{C}$		8.7 8.3		S	Fig. 4
Drain-Source On-State Resistance	R _{DS(ON)}	$V_{GS} = 20 \text{ V, } I_D = 20 \text{ A}$ $V_{GS} = 20 \text{ V, } I_D = 20 \text{ A, } T_j = 175 ^{\circ}\text{C}$		75 116	90	mΩ	Fig. 5-8
Input Capacitance	Ciss	V _{DS} = 800 V, V _{GS} = 0 V f = 1 MHz, V _{AC} = 25mV		1053			Fig. 11
Output Capacitance	Coss			75		pF	
Reverse Transfer Capacitance	Crss			6.7			
Coss Stored Energy	Eoss			46		μJ	Fig. 12
Coss Stored Charge	Qoss			92		nC	
Gate-Source Charge	Q _{gs}	V_{DS} = 800 V, V_{GS} = -5 / +20 V I_{D} = 20 A Per IEC607478-4		12			
Gate-Drain Charge	Q _{gd}			19		nC	Fig. 10
Total Gate Charge	Qg			55			
Internal Gate Resistance	R _{G(int)}	f = 1 MHz, V _{AC} = 25 mV		1.8		Ω	

Reverse Diode Characteristics								
Parameter	Symbol	Conditions	Values			Unit	Note	
			Min.	Тур.	Max.	- Unit	Note	
Diode Forward Voltage	V_{SD}	$V_{GS} = -5 \text{ V, } I_{SD} = 10 \text{ A}$		4.5		V	Fig.	
		$V_{GS} = -5 \text{ V, } I_{SD} = 10 \text{ A, } T_j = 175^{\circ}\text{C}$		4.0		V	17-18	
Continuous Diode Forward Current	Is	$V_{GS} = -5 \text{ V, } T_c = 100^{\circ}\text{C}$		12		Α		
Diode Pulse Current	I _{S(pulse)}	V _{GS} = -5 V, Note 1		80		Α		
	·							



Figure 1: Output Characteristics (T_i = 25°C)

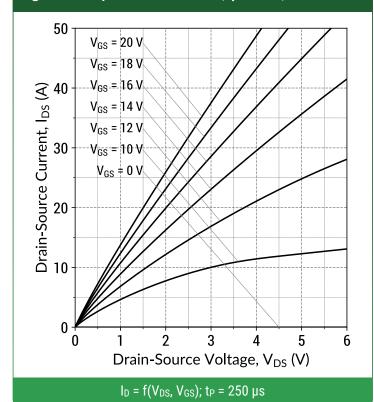
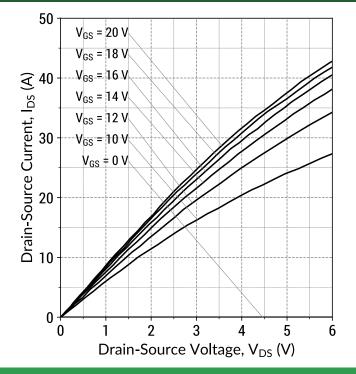


Figure 2: Output Characteristics (T_i = 175°C)



 $I_D = f(V_{DS}, V_{GS}); t_P = 250 \mu s$

Figure 3: Output Characteristics (V_{GS} = 20 V)

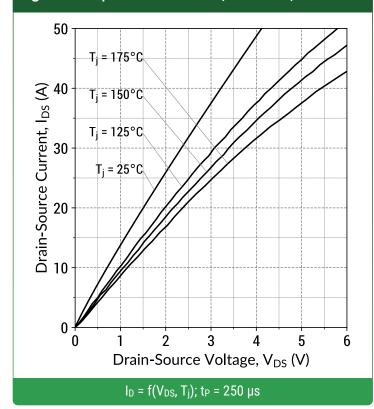
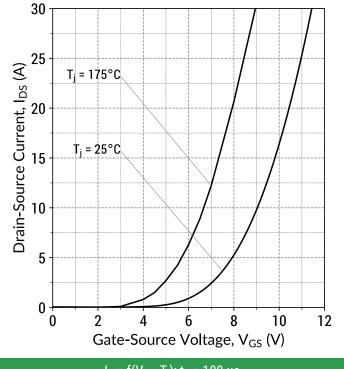


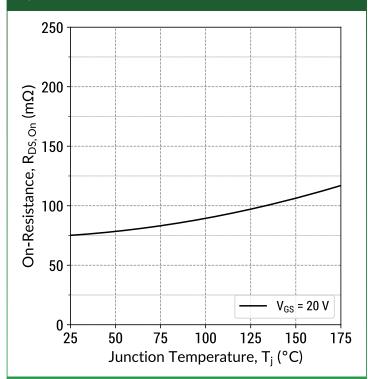
Figure 4: Transfer Characteristics (V_{DS} = 10 V)



 $I_D = f(V_{GS}, T_j); t_P = 100 \ \mu s$

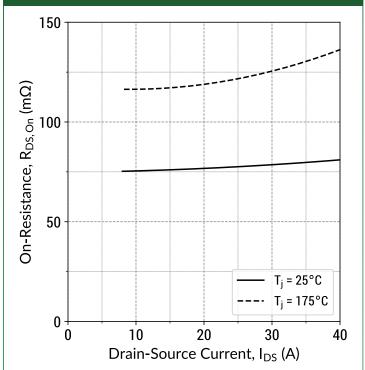






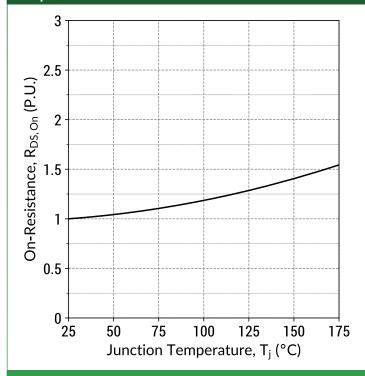
 $R_{DS(ON)} = f(T_j, V_{GS}); t_P = 250 \mu s; I_D = 20 A$

Figure 6: On-State Resistance v/s Drain Current



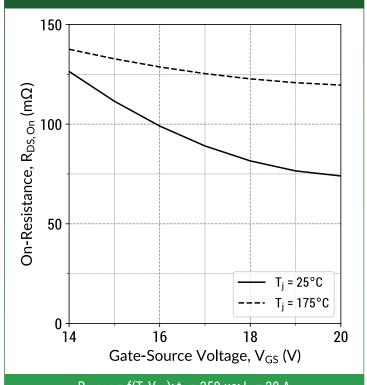
 $R_{DS(ON)} = f(T_j,I_D); t_P = 250 \ \mu s; V_{GS} = 20 \ V$

Figure 7: Normalized On-State Resistance v/s Temperature



 $R_{DS(ON)} = f(T_i); t_P = 250 \mu s; I_D = 20 A; V_{GS} = 20 V$

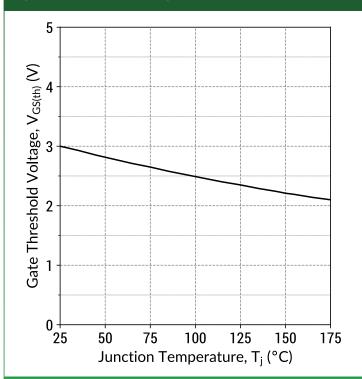
Figure 8: On-State Resistance v/s Gate Voltage



 $R_{DS(ON)} = f(T_j, V_{GS}); t_P = 250 \ \mu s; I_D = 20 \ A$

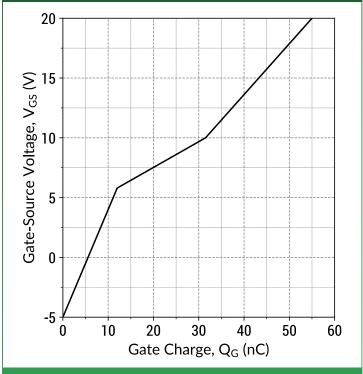






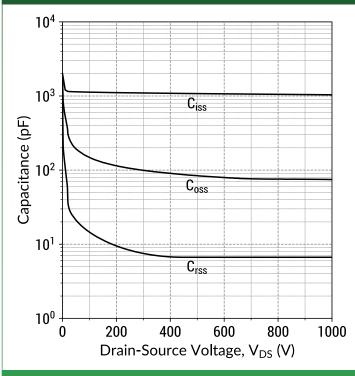
 $V_{GS(th)} = f(T_j); V_{DS} = V_{GS}; I_D = 7.5 \text{ mA}$

Figure 10: Gate Charge Characteristics



 $I_D = 20 \text{ A}$; $V_{DS} = 800 \text{ V}$; $T_c = 25^{\circ}\text{C}$

Figure 11: Capacitance v/s Drain-Source Voltage



 $f = 1 MHz; V_{AC} = 25mV$

Figure 12: Output Capacitor Stored Energy

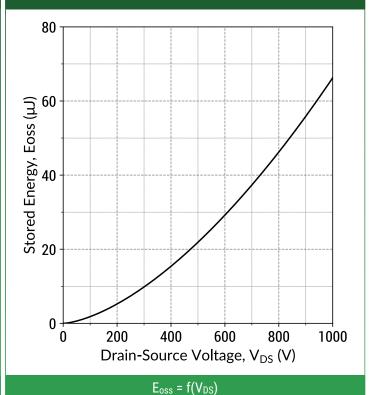
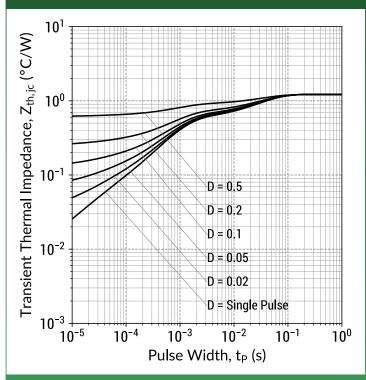


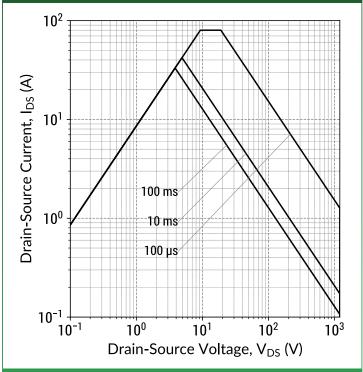


Figure 13: Transient Thermal Impedance



 $Z_{th,jc} = f(t_P,D); D = t_P/T$

Figure 14: Safe Operating Area ($T_c = 25$ °C)



 $I_D = f(V_{DS}, t_P); T_j \le 175^{\circ}C; D = 0$

Figure 15: Current De-rating Curve

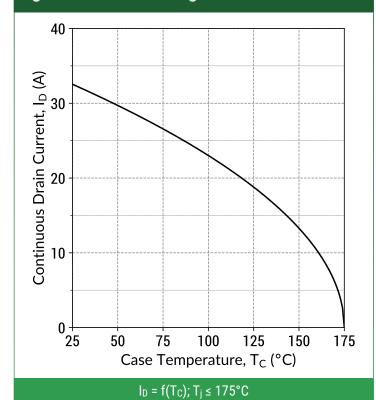


Figure 16: Power De-rating Curve

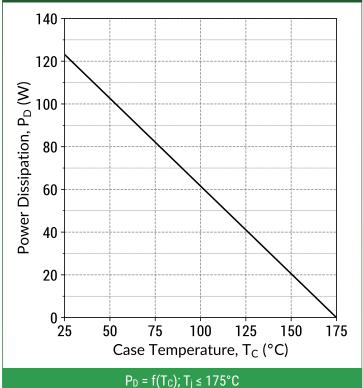
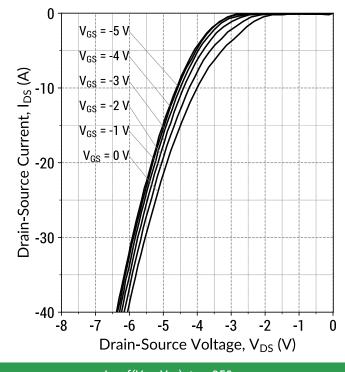


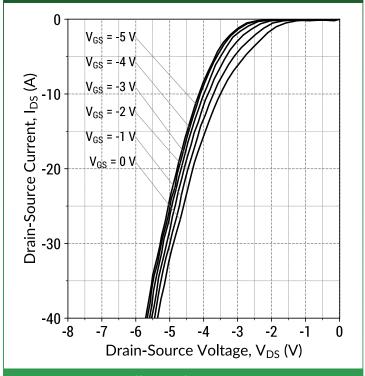


Figure 17: Body Diode Characteristics (T_i = 25°C)



 $I_D = f(V_{DS}, V_{GS}); t_P = 250 \ \mu s$

Figure 18: Body Diode Characteristics (T_i = 175°C)



 $I_D = f(V_{DS}, V_{GS}); t_P = 250 \ \mu s$

Figure 19: Third Quadrant Characteristics ($T_j = 25$ °C)

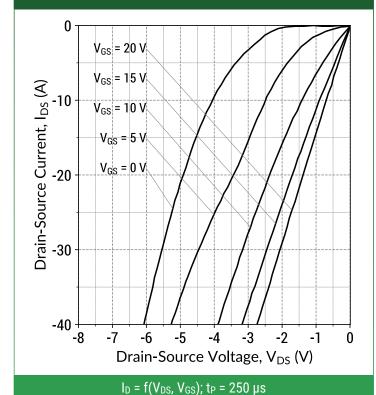
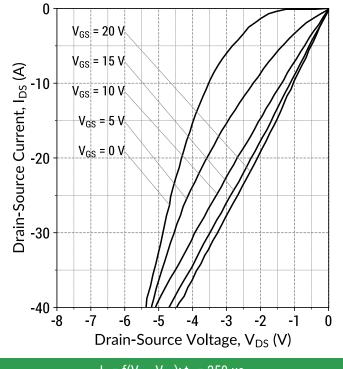


Figure 20: Third Quadrant Characteristics ($T_j = 175$ °C)



 $I_D = f(V_{DS}, V_{GS}); t_P = 250 \ \mu s$



RoHS Compliance

The levels of RoHS restricted materials in this product are below the maximum concentration values (also referred to as the threshold limits) permitted for such substances, or are used in an exempted application, in accordance with EU Directive 2011/65/EC (RoHS 2), as adopted by EU member states on January 2, 2013 and amended on March 31, 2015 by EU Directive 2015/863. RoHS Declarations for this product can be obtained from your GeneSiC representative.

REACH Compliance

REACH substances of high concern (SVHCs) information is available for this product. Since the European Chemical Agency (ECHA) has published notice of their intent to frequently revise the SVHC listing for the foreseeable future, please contact a GeneSiC representative to insure you get the most up-to-date REACH SVHC Declaration. REACH banned substance information (REACH Article 67) is also available upon request.

This product has not been designed or tested for use in, and is not intended for use in, applications implanted into the human body nor in applications in which failure of the product could lead to death, personal injury or property damage, including but not limited to equipment used in the operation of nuclear facilities, life-support machines, cardiac defibrillators or similar emergency medical equipment, aircraft navigation or communication or control systems, or air traffic control systems.

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